

Search Notes

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

NAKAMURA, SHINICHI

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22-35,85 89,92	11/29/2005	<i>SWH</i> SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
USPGPUB text search (see attached)		11/29/2005	<i>SWH</i> SWH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR